

# CERTIFICATE OF ACCREDITATION

## The ANSI National Accreditation Board

Hereby attests that

# **GD4** Test Services, Inc.

5301 Riata Park Court, Building E Ste 120A Austin, TX 78727 (and the satellite locations as listed on the scope)

Fulfills the requirements of

## **ISO/IEC 17025:2017**

and the

**AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program** 

In the field of

## **TESTING**

This certificate is valid only when accompanied by a current scope of accreditation document. The current scope of accreditation can be verified at <a href="www.anab.org">www.anab.org</a>.

Jason Stine, Vice President

Expiry Date: 29 July 2024 Certificate Number: AT-2892









# SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017 and AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

## **GD4** Test Services, Inc.

5301 Riata Park Court, Building E Ste 120A Austin, TX 78727 George Jastroch gj@gd4test.com 512 535 1677

## **TESTING**

Valid to: July 29, 2024 Certificate Number: AT-2892

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to GD4 Test Services, Inc. to perform the following AS6171 slash sheet tests:

#### Mechanical

Version 006 Issued: July 6, 2023

Specific Tests and/or	Specification, Standard,	Items, Materials or	Key Equipment or
Properties Measured	Method, or Test Technique	Product Tested	Technology
Decapsulation	AS6081, Sect. 4.2.6.4.6, AS6171/4 Sect. 3.1 – 3.7	Electronic Components	Hotplate, Multiple Acids
Heated Chemical Test	AS6081, Sect. 4.2.6.4.3, AS6171/2, Sect. 5.3.4 Method D		Multiple Chemicals
X-Ray Inspection	AS6081, Sect. 4.2.6.4.4, AS6171/5		Focal Spot X-Ray
XRF Inspection	AS6081, Sect. 4.2.6.4.5, AS6171/3		Quickshot XRF
Temperature Cycle	MIL-STD-883, Method 1010, AS6081 Sect. C.2 AS6171/7		Blue M Temperature Cycle Chamber
C-SAM	AS6081, Sect. C.6		OKOS Sonoscan
Visual Inspection	AS6081, Sect. 4.2.6.4.2, AS6171/2, Method A and B, AS6171/2, Method E		Multiple Scopes Scale
SEM Surface Texture Analysis	AS6171/2 Method F		Vega Tescan



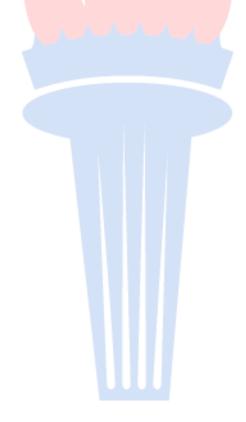


## Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Solderability	J-STD-002 MIL-STD-883	Electronic Components	Solder Pot AM Scope Stream Ager
Resistance to Solvents	AS6081, Sect. 4.2.6.4.3-A, AS6171/2, Method C		Multiple Chemicals

## **Electrical**

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Electrical Test: Resistors,			
Capacitors, Inductors, Relays,	AS617 <mark>1/7 Table 2,</mark>	Electronic Components	Multiple A.T.E. Equipment
connectors, Microcircuits and	AS6081, Sect. C.3	Electronic Components	Sets
Semiconductor devices			







## **SATELLITE SITE**

## GD4 Test Services, Inc.

12505 Starkey Road, Suite N Largo, FL 33773 George Jastroch gj@gd4test.com 512 535 1677

## **TESTING**

### Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Produ <mark>c</mark> t Tested	Key Equipment or Technology
Decapsulation	AS6081, Sect. 4.2.6.4.6, AS6171/4 Sect. 3.1 – 3.7	Electronic Components	Hotplate, Multiple Acids
Heated Chemical Test	AS6081, Sect. 4.2.6.4.3, AS6171/2, Sect. 5.3.4 Method D		Multiple Chemicals
X-Ray Inspection	AS6081, Sect. 4.2.6.4.4, AS6171/5		Focal Spot X-Ray
XRF Inspection	AS6081, Sect. 4.2.6.4.5, AS6171/3		Quickshot XRF
Visual Inspection	AS6081, Sect. 4.2.6.4.2, AS6171/2, Method A and B, AS6171/2, Method E		Multiple Scopes Scale
Solderability	J-STD-002 MIL-STD-883		Solder Pot AM Scope Stream Ager
Resistance to Solvents	AS6081, Sect. 4.2.6.4.3-A, AS6171/2, Method C		Multiple Chemicals

## **Electrical**

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Specific Tests and/or	Specification, Standard,	Items, Materials or	Key Equipment or
Properties Measured	Method, or Test Technique	Product Tested	Technology
Electrical Test	AS6171/7 AS6081 – C.3	Electronic Components	Multiple A.T.E. Equipment Sets

ANAB
ANSI National Accreditation Board



## **SATELLITE SITE**

## **GD4** Test Services, Inc.

95 Horseblock Road, Suite 3 Yaphank, NY 11980 George Jastroch gj@gd4test.com 512 535 1677

## **TESTING**

### Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Decapsulation	AS6081, Sect. 4.2.6.4.6, AS6171/4 Sect. 3.1 – 3.7		Hotplate, Multiple Acids
Heated Chemical Test	AS6081, Sect. 4.2.6.4.3, AS6171/2, Sect. 5.3.4 Method D	4	Multiple Chemicals
X-Ray Inspection	AS6081, Sect. 4.2.6.4.4, AS6171/5	Electronic Components	Focal Spot X-Ray
XRF Inspection	AS6081, Sect. 4.2.6.4.5, AS6171/3		Quickshot XRF
Visual Inspection	AS6081, Sect. 4.2.6.4.2, AS6171/2, Method A and B, AS6171/2A, Method E		Multiple Scopes Scale
Solderability	J-STD-002 MIL-STD-883		Solder Pot AM Scope Stream Ager
Resistance to Solvents	AS6081, Sect. 4.2.6.4.3-A, AS6171/2, Method C		Multiple Chemicals



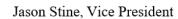


### **Electrical**

Specific Tests and/or	Specification, Standard,	Items, Materials or	Key Equipment or
Properties Measured	Method, or Test Technique	Product Tested	Technology
Electrical Test: Resistors, Capacitors, Inductors, Relays, connectors, Microcircuits and Semiconductor devices		Electronic Components	Multiple A.T.E. Equipment Sets

#### Note:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-2892.



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